

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



### Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China







TOSHIBA Photocoupler GaAlAs Ired & Photo-IC

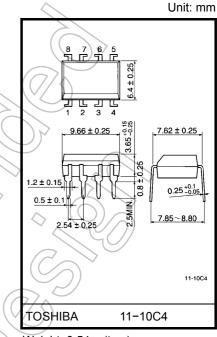
## **TLP2200**

Isolated Bus Driver
High Speed Line Receiver
Microprocessor System Interfaces
MOS FET Gate Driver
Direct Replacement for HCPL-2200

The TOSHIBA TLP2200 consists of a GaA $\ell$ As light emitting diode and integrated high gain, high speed photodetector. This unit is 8–lead DIP package.

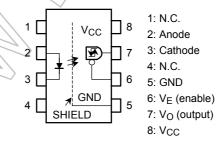
The detector has a three state output stage that eliminates the need for pull–up resistor, and built–in Schmitt trigger. The detector IC has an internal shield that provides a guaranteed common mode transient immunity of  $1000V\,/\,\mu s$ .

- Input current: I<sub>F</sub> = 1.6 mA
- Power supply voltage:  $V_{CC} = 4.5 \sim 20 \text{ V}$
- Switching speed: 2.5MBd guaranteed
- Common mode transient immunity: ±1000V / µs (min)
- Guaranteed performance over temperature: 0~85°C
- Isolation voltage: 2500 Vrms (min)
- UL recognized: UL1577, file No. E67349

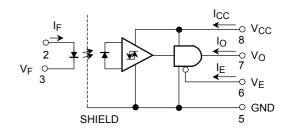


Weight: 0.54 g (typ.)

### Pin Configuration (top view)



### **Schematic**



### Truth Table (positive logic)

Input	Enable	Output
Н	Н	$(\langle z \rangle)$
L	H	Z
Н	4	F
L	L	L

### **Recommended Operating Conditions**

Characteristic	Symbol	Min	Тур.	Max	Unit
Input current, on	I <sub>F(ON)</sub>	1.6	1	5	mA
Input current, off	I <sub>F(OFF)</sub>	0	1	0.1	mA
Supply voltage	V <sub>CC</sub>	4.5	ı	20	V
Enable voltage high	V <sub>EH</sub>	2.0	1	20	٧
Enable voltage low	V <sub>EL</sub>	0	_	0.8	٧
Fan out (TTL load)	N	_	_	4	_
Operating temperature	T <sub>opr</sub>	0	_	85	√°C (

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

### Absolute Maximum Ratings (no derating required up to 70°C)

	Characteristic	Symbol	Rating	Unit
٥	Forward current	IF 🗸	10	mA (
Ш	Peak transient forward current (Note 1)	IFPT	ľ	A
_	Reverse voltage	VR	5	(V//
_	Output current	/(lo)	25	mA
c t o	Supply voltage	Vcc	-0.5~20	Y
e e	Output voltage	Yo	-0.5~20	\\\
e t	Three state enable voltage	V <sub>E</sub>	-0.5~20	V
Ω	Total package power dissipation (Note 2)	PT	210	mW
Оре	rating temperature range	T <sub>opr</sub>	-40~85	°C
Stor	age temperature range	T <sub>stg</sub>	-55~125	°C
Lead	d solder temperature (10s) (**)	T <sub>sol</sub>	260	°C
	tion voltage 1minute, R.H. ≤ 60%,Ta = 25°C) (Note 3)	BVS	2500	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(Note 1) Pulse width 1µs, 300 pps.

(Note 2) Derate 4.5mW / °C above 70°C ambient temperature.

(Note 3) Device considered a two terminal device: Pins 1, 2, 3 and 4 shorted together, and pins 5,6,7 and 8 shorted together

(\*\*) 1.6mm below seating plane.

# Electrical Characteristics (unless otherwise specified, Ta = 0~85°C, $V_{CC}$ = 4.5~20V, $I_{F(ON)}$ = 1.6~5mA, $I_{F(OFF)}$ = 0~0.1mA, $V_{EL}$ = 0~0.8V, $V_{EH}$ = 2.0~20V)

Characteristic	Symbol	Test Condition		Min	Typ.*	Max	Unit	
Output leakage current		I <sub>F</sub> = 5mA,	V <sub>O</sub> = 5.5V	_	_	100		
(V <sub>O</sub> > V <sub>CC</sub> )	Іонн	V <sub>CC</sub> = 4.5V V <sub>O</sub> = 20V		- <	2	500	μΑ	
Logic low output voltage	$V_{OL}$	I <sub>OL</sub> = 6.4mA (4 TT	L load)		0.32	0.5	>	
Logic high output voltage	$V_{OH}$	I <sub>OH</sub> = -2.6mA		2.4	3.4	_	<b>V</b>	
Logic low enable current	I <sub>EL</sub>	V <sub>E</sub> = 0.4V		(a)	-0.13	-0.32	mA	
		V <sub>E</sub> = 2.7V	\ <u>\</u>		))_	20		
Logic high enable current	I <sub>EH</sub>	V <sub>E</sub> = 5.5V		) \	_	100	μΑ	
		V <sub>E</sub> = 20V			0.01	250		
Logic low enable voltage	V <sub>EL</sub>	-	- (	)	- (	0.8	V	
Logic high enable voltage	V <sub>EH</sub>	-	-	2.0	7		V	
1 - 2 - 1 - 1 - 1 - 1 - 1 - 1 - 1		I <sub>F</sub> = 0mA	V <sub>CC</sub> = 5.5V		5	6.0	A	
Logic low supply current	ICCL	V <sub>E</sub> = don't care	V <sub>CC</sub> = 20V		5.6	7).5	mA	
Lania biah awantu awasat	1	I <sub>F</sub> = 5mA V <sub>E</sub> = don't care	V <sub>CC</sub> = 5.5V	-(3	2.5	4.5	mA	
Logic high supply current	ICCH		V <sub>CC</sub> = 20V	<del>(</del> C	2.8	6.0		
	I <sub>OZL</sub>	I <sub>F</sub> = 5mA V <sub>E</sub> = 2V	V <sub>O</sub> = 0.4V			-20		
High impedance state	lozh	I <sub>F</sub> = 0mA V <sub>E</sub> = 2V	V <sub>O</sub> = 2.4V		_	20	μΑ	
output current			V <sub>O</sub> = 5.5V	_	_	100		
	(	VE ZV	V <sub>O</sub> = 20V	))_	0.01	500		
Logic low short circuit	. (		V <sub>O</sub> = V <sub>CC</sub> = 5.5V	25	55	_		
output current (Note 4)	losi	I <sub>F</sub> = 0mA	V <sub>O</sub> = V <sub>CC</sub> = 20V	40	80	_	mA	
Logic high short circuit		I <sub>F</sub> = 5mA	V <sub>CC</sub> = 5.5V	-10	-25	_	A	
output current (Note 4)	losh	V <sub>O</sub> = GND	V <sub>CC</sub> = 20V	-25	-60	_	mA	
Input current hysteresis	IHYS	V <sub>CC</sub> = 5V		_	0.05	_	mA	
Input forward voltage	VF	I <sub>F</sub> = 5mA, Ta = 25°C		_	1.55	1.7	V	
Temperature coefficient of forward voltage	ΔV <sub>F</sub> / ΔTa	I <sub>F</sub> = 5mA		_	-2.0	_	mV / °C	
Input reverse breakdown voltage	BV <sub>R</sub>	I <sub>R</sub> = 10μA, Ta = 25°C		5	_	_	٧	
Input capacitance	CIN	V <sub>F</sub> = 0V, f = 1MHz, Ta = 25°C		_	45	_	pF	
Resistance (input-output)	R <sub>I-O</sub>	V <sub>I–O</sub> = 500V R.H. ≤ 60% (Note 3)		5×10 <sup>10</sup>	10 <sup>14</sup>	_	Ω	
Capacitance (input-output)	CIO	V <sub>I-O</sub> = 0V, f = 1M	_	0.6	_	pF		

<sup>(\*\*)</sup> All typ. values are at Ta = 25°C, V<sub>CC</sub> = 5V, I<sub>F(ON)</sub> = 3mA unless otherwise specified.

3 2014-09-01

## Switching Characteristics (unless otherwise specified, Ta = $0~85^{\circ}$ C, $V_{CC} = 4.5~20$ V, $I_{F(ON)} = 1.6~5$ mA, $I_{F(OFF)} = 0~0.1$ mA)

Characteristic		Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Propagation delay time to		<b>+</b>		Without peaking capacitor	_	235	_	no
logic high output level	(Note 5)	t <sub>pLH</sub>		With peaking capacitor C <sub>1</sub>	/	_	400	ns
Propagation delay time to logic low output level	(Note 5)	t <sub>pHL</sub>	1	Without peaking capacitor C <sub>1</sub> With peaking capacitor C <sub>1</sub>		250	400	ns
Output rise time (10–90%)	(11010 0)	t <sub>r</sub>		With peaking supusitor of	>=	35	<del></del>	ns
Output fall time (90–10%)		t <sub>f</sub>		- ((//		20	_	ns
Output enable time to logic high		t <sub>pZH</sub>		-	_	_	_	ns
Output enable time to logic low		t <sub>pZL</sub>		-	_	_	_	ns
Output disable time from logic high		t <sub>pHZ</sub>	2	4()	_	A CO	<i>\rightarrow</i>	ns
Output disable time from logic low		$t_{pLZ}$		(7/5)	-(		> _	ns
Common mode transient immunity at logic high output	(Note 6)	CM <sub>H</sub>		$I_F = 1.6$ mA, $V_{CM} = 50$ V, $Ta = 25$ °C	-1000		_	V / µs
Common mode transient immunity at logic low output	(Note 6)	CML	3	I <sub>F</sub> = 0mA, V <sub>CM</sub> = 50V, Ta = 25°C	1000	_	_	V / µs

(\*) All typ. values are at Ta = 25°C, V<sub>CC</sub> = 5V, I<sub>F(ON)</sub> = 3mA unless otherwise specified.

(Note 4) Duration of output short circuit time should not exceed 10ms.

(Note 5) The t<sub>pLH</sub> propagation delay is measured from the 50% point on the leading edge of the input pulse to the 1.3V point on the leading edge of the output pulse.

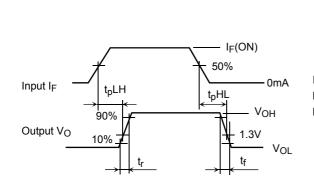
The t<sub>pHL</sub> propagation delay is measured from the 50% point on the trailing edge of the input pulse to the 1.3V point on the trailing edge of the output pulse.

(Note 6) CM<sub>L</sub> is the maximum rate of rise of the common mode voltage that can be sustained with the output voltage in the logic low state ( $V_O \le 0.8V$ ).

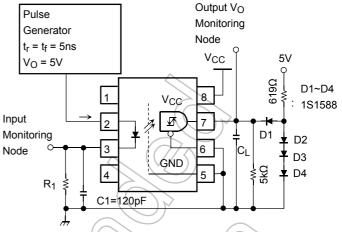
 $CM_H$  is the maximum rate of fall of the common mode voltage that can be sustained with the output voltage in the logic high state ( $V_O \le 2.0V$ ).



### Test Circuit 1 $t_{pHL}$ , $t_{pLH}$ , $t_r$ and $t_f$



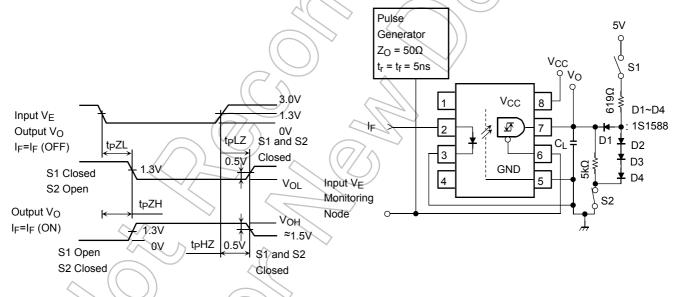
R <sub>1</sub>	2.15kΩ	1.1kΩ	681Ω
I <sub>F</sub> (ON)	1.6mA	3mA	5mA



C<sub>1</sub> is peaking capacitor. The probe and jig capacitances are included in C<sub>1</sub>.

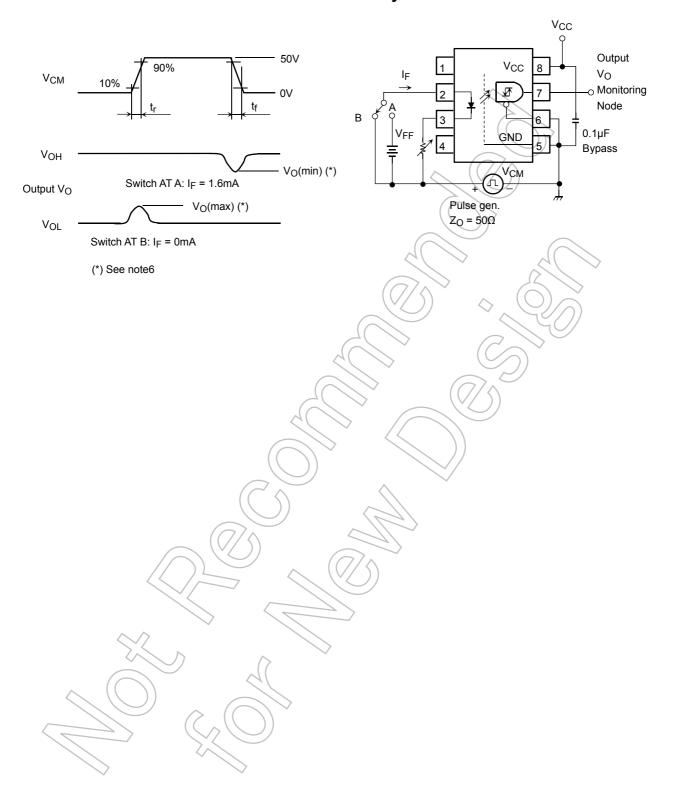
C<sub>L</sub> is approximately 15pF which includes probe and stray wiring capacitance.

## Test Circuit 2 $t_{pHZ}$ , $t_{pZH}$ , $t_{pLZ}$ and $t_{pZL}$



C<sub>L</sub> is approximately 15pF which includes probe and stray wiring capacitance.

### **Test Circuit 3 Common Mode Transient Immunity**



6 2014-09-01

#### **RESTRICTIONS ON PRODUCT USE**

- Toshiba Corporation, and its subsidiaries and affiliates (collectively "TOSHIBA"), reserve the right to make changes to the information in this document, and related hardware, software and systems (collectively "Product") without notice.
- This document and any information herein may not be reproduced without prior written permission from TOSHIBA. Even with TOSHIBA's written permission, reproduction is permissible only if reproduction is without alteration/omission.
- Though TOSHIBA works continually to improve Product's quality and reliability, Product can malfunction or fail. Customers are responsible for complying with safety standards and for providing adequate designs and safeguards for their hardware, software and systems which minimize risk and avoid situations in which a malfunction or failure of Product could cause loss of human life, bodily injury or damage to property, including data loss or corruption. Before customers use the Product, create designs including the Product, or incorporate the Product into their own applications, customers must also refer to and comply with (a) the latest versions of all relevant TOSHIBA information, including without limitation, this document, the specifications, the data sheets and application notes for Product and the precautions and conditions set forth in the "TOSHIBA Semiconductor Reliability Handbook" and (b) the instructions for the application with which the Product will be used with or for. Customers are solely responsible for all aspects of their own product design or applications, including but not limited to (a) determining the appropriateness of the use of this Product in such design or applications; (b) evaluating and determining the applicability of any information contained in this document, or in charts, diagrams, programs, algorithms, sample application circuits, or any other referenced documents; and (c) validating all operating parameters for such designs and applications. TOSHIBA ASSUMES NO LIABILITY FOR CUSTOMERS PRODUCT DESIGN OR APPLICATIONS.
- PRODUCT IS NEITHER INTENDED NOR WARRANTED FOR USE IN EQUIPMENTS OR SYSTEMS THAT REQUIRE
  EXTRAORDINARILY HIGH LEVELS OF QUALITY AND/OR RELIABILITY, AND/OR A MALFUNCTION OR FAILURE OF WHICH
  MAY CAUSE LOSS OF HUMAN LIFE, BODILY INJURY, SERIOUS PROPERTY DAMAGE AND/OR SERIOUS PUBLIC IMPACT
  ("UNINTENDED USE"). Except for specific applications as expressly stated in this document, Unintended Use includes, without
  limitation, equipment used in nuclear facilities, equipment used in the aerospace industry, medical equipment, equipment used for
  automobiles, trains, ships and other transportation, traffic signaling equipment, equipment used to control compustions or explosions,
  safety devices, elevators and escalators, devices related to electric power, and equipment used in finance-related fields. IF YOU USE
  PRODUCT FOR UNINTENDED USE, TOSHIBA ASSUMES NO LIABILITY FOR PRODUCT. For details, please contact your
  TOSHIBA sales representative.
- . Do not disassemble, analyze, reverse-engineer, alter, modify, translate or copy Product, whether in whole or in part.
- Product shall not be used for or incorporated into any products or systems whose manufacture, use, or sale is prohibited under any
  applicable laws or regulations.
- The information contained herein is presented only as guidance for Product use. No responsibility is assumed by TOSHIBA for any infringement of patents or any other intellectual property rights of third parties that may result from the use of Product. No license to any intellectual property right is granted by this document, whether express or implied, by estoppel or otherwise.
- ABSENT A WRITTEN SIGNED AGREEMENT, EXCEPT AS PROVIDED IN THE RELEVANT TERMS AND CONDITIONS OF SALE
  FOR PRODUCT, AND TO THE MAXIMUM EXTENT ALLOWABLE BY LAW, TOSHIBA (1) ASSUMES NO LIABILITY
  WHATSOEVER, INCLUDING WITHOUT LIMITATION, INDIRECT, CONSEQUENTIAL, SPECIAL, OR INCIDENTAL DAMAGES OR
  LOSS, INCLUDING WITHOUT LIMITATION, LOSS OF PROFITS, LOSS OF OPPORTUNITIES, BUSINESS INTERRUPTION AND
  LOSS OF DATA, AND (2) DISCLAIMS ANY AND ALL EXPRESS OR IMPLIED WARRANTIES AND CONDITIONS RELATED TO
  SALE, USE OF PRODUCT, OR INFORMATION, INCLUDING WARRANTIES OR CONDITIONS OF MERCHANTABILITY, FITNESS
  FOR A PARTICULAR PURPOSE, ACCURACY OF INFORMATION, OR NONINFRINGEMENT.
- GaAs (Gallium Arsenide) is used in Product. GaAs is harmful to humans if consumed or absorbed, whether in the form of dust or vapor.
   Handle with care and do not break, cut, crush, grind, dissolve chemically or otherwise expose GaAs in Product.
- Do not use or otherwise make available Product or related software or technology for any military purposes, including without limitation, for the design, development, use, stockpiling or manufacturing of nuclear, chemical, or biological weapons or missile technology products (mass destruction weapons). Product and related software and technology may be controlled under the applicable export laws and regulations including, without limitation, the Japanese Foreign Exchange and Foreign Trade Law and the U.S. Export Administration Regulations. Export and re-export of Product or related software or technology are strictly prohibited except in compliance with all applicable export laws and regulations.
- Please contact your TOSHIBA sales representative for details as to environmental matters such as the RoHS compatibility of Product.
   Please use Product in compliance with all applicable laws and regulations that regulate the inclusion or use of controlled substances, including without limitation, the EU RoHS Directive. TOSHIBA ASSUMES NO LIABILITY FOR DAMAGES OR LOSSES
   OCCURRING AS A RESULT OF NONCOMPLIANCE WITH APPLICABLE LAWS AND REGULATIONS.